- Compares Two 8-Bit Words
- Flow-Through Architecture Optimizes
  PCB Layout
- Center-Pin V<sub>CC</sub> and GND Configurations Minimize High-Speed Switching Noise
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages, Plastic Shrink Small-Outline Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

### description

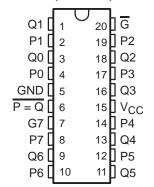
These identity comparators perform comparisons on two 8-bit binary or BCD words. Also included is a  $\overline{P} = \overline{Q}$  totem-pole output.

The 54AC11521 is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to 125°C. The 74AC11521 is characterized for operation from  $-40^{\circ}$ C to 85°C.

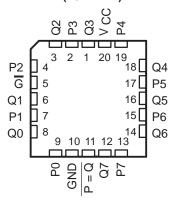
#### **FUNCTION TABLE**

INF	PUTS	OUTPUT
DATA P, Q	ENABLE G	P = Q
P = Q	L	L
P > Q	L	Н
P < Q	L	Н
Х	Н	Н

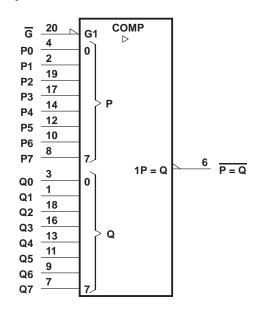
#### 54AC11521 . . . J PACKAGE 74AC11521 . . . DB, DW OR N PACKAGE (TOP VIEW)



# 54AC11521 . . . FK PACKAGE (TOP VIEW)



### logic symbol†



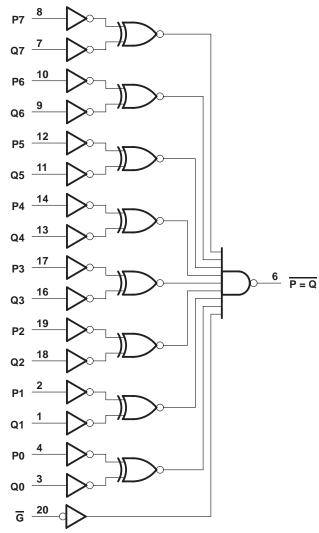
<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pins numbers shown are for the DW, J, and N packages.

EPIC is a trademark of Texas Instruments Incorporated.



### logic diagram (positive logic)



Pin numbers shown are for the DW, J, and N packages.

# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	0.5 V to 6 V
Input voltage range, V <sub>I</sub> (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, V <sub>O</sub> (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )	± 20 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> )	± 50 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	± 50 mA
Continuous current through V <sub>CC</sub> or GND	±100 mA
Storage temperature range	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



# recommended operating conditions

			54	1AC1152	:1	74AC11521		UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		3	5	5.5	3	5	5.5	V
		V <sub>CC</sub> = 3 V	2.1			2.1			
ViH	High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15			3.15			V
		V <sub>CC</sub> = 5.5 V	3.85			3.85			
V <sub>IL</sub> Low-level input voltage		VCC = 3 V			0.9			0.9	
	V <sub>CC</sub> = 4.5 V			1.35			1.35	V	
		V <sub>CC</sub> = 5.5 V			1.65			1.65	
VI	Input voltage		0		VCC	0		VCC	V
٧o	Output voltage		0		VCC	0		VCC	V
		VCC = 3 V			- 4			- 4	
IOH	High-level output current	V <sub>CC</sub> = 4.5 V			- 24			- 24	mA
		V <sub>CC</sub> = 5.5 V			-24			-24	
		V <sub>CC</sub> = 3 V			12			12	
lOL	Low-level output current	V <sub>CC</sub> = 4.5 V			24			24	mA
		V <sub>CC</sub> = 5.5 V			24			24	
Δt/Δν	Input transition rise or fall rate		0		10	0		10	ns/V
T <sub>A</sub>	Operating free-air temperature		-55		125	- 40		85	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED TEST CONDITIONS			T,	Δ = 25°C	;	54AC1	1521	74AC11521		LINUT
PARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
		3 V	2.9			2.9		2.9		
	ΙΟΗ = – 50 μΑ	4.5 V	4.4			4.4		4.4		
		5.5 V	5.4			5.4		5.4		
V	$I_{OH} = -4 \text{ mA}$	3 V	2.58			2.4		2.48		.,
VOH	1011 - 24 mA	4.5 V	3.94			3.7		3.8		V
	I <sub>OH</sub> = – 24 mA	5.5 V	4.94			4.7		4.8		7
	$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V				3.85				
	I <sub>OH</sub> = -75 mA <sup>†</sup>	5.5 V						3.85		
	Ι <sub>ΟL</sub> = 50 μΑ	3 V			0.1		0.1		0.1	
		4.5 V			0.1		0.1		0.1	
		5.5 V			0.1		0.1		0.1	
V	I <sub>OL</sub> = 12 mA	3 V			0.36		0.5		0.44	V
VOL	I <sub>OL</sub> = 24 mA	4.5 V			0.36		0.5		0.44	V
	10L - 24 111A	5.5 V			0.36		0.5		0.44	
	$I_{OL} = 50 \text{ mA}^{\dagger}$	5.5 V					1.65			
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V							1.65	
lį	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V			± 0.1		± 1		± 1	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		160		80	μΑ
Ci	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		4						pF

<sup>†</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.



SCAS022A - D2957, JULY 1987 - REVISED APRIL 1993

# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T,	4 = 25°C	;	54AC1	11521	74AC1	11521	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
<sup>t</sup> PLH	P or Q		1.5	12.5	16.6	1.5	20.4	1.5	19		
<sup>t</sup> PHL	POIQ	P = Q	P=Q	1.5	10.5	14.1	1.5	17.4	1.5	16.1	ns
t <sub>PLH</sub>	G		1.5	7.1	9.8	1.5	11.4	1.5	10.8		
t <sub>PHL</sub>	]	P = Q	1.5	6.4	8.8	1.5	10.8	1.5	10.1	ns	

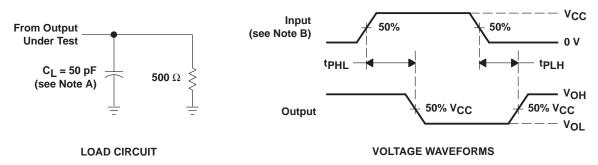
# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T,	չ = 25°C	;	54AC1	1521	74AC1	1521	UNIT		
PARAIVIETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT		
<sup>t</sup> PLH	P or Q		1.5	8.3	11.3	1.5	14	1.5	13	no		
t <sub>PHL</sub>	Police	P = Q	P=Q	P = Q	1.5	7.2	10.1	1.5	12.2	1.5	11.4	ns
t <sub>PLH</sub>	G		1.5	5.1	7.1	1.5	8.4	1.5	7.9	no		
t <sub>PHL</sub>	G	P = Q	1.5	4.8	7.1	1.5	8.6	1.5	8.1	ns		

# operating characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{C}$

PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub> Power dissipation capacitance	$C_L = 50 \text{ pF}, \qquad \qquad f = 1 \text{ MHz}$	42	pF

#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \ \Omega$ ,  $t_f = 3 \ ns$ ,  $t_f = 3 \ ns$ .
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

#### **IMPORTANT NOTICE**

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 1998, Texas Instruments Incorporated